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Applicant(s)/Patent Under Reexamination

SATOH ET AL.

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Art Unit 2627

HENOK G HEYI

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SEARCH NOTES			
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Searched EAST. Some of the subclasses searched are 369/30.23 and 47.1 (text search only - please see search history printout).	02/29/2009	НН	

INTERFERENCE SEARCH			
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